

MJLM124-X REV 1B1

Original Creation Date: 07/19/95

Last Update Date: 03/28/02

Last Major Revision Date: 03/16/00

QUAD OPERATIONAL AMPLIFIER, SINGLE SUPPLY, LOW POWER
General Description

The LM124 consists of four independent, high gain, internally frequency compensated operational amplifiers which were designed specifically to operate from a single power supply over a wide range of voltages. Operation from split power supplies is also possible and the low power supply current drain is independent of the magnitude of the power supply voltage.

Application areas include transducer amplifiers, DC gain blocks and all the conventional op amp circuits which now can be more easily implemented in single power supply systems. For example, the LM124 can be directly operated off of the standard +5 VDC power supply voltage which is used in digital systems and will easily provide the required interface electronics without requiring the additional ± 15 VDC power supplies.

Industry Part Number

LM124

Prime Die

LM124

NS Part Numbers

JL124BCA

JL124BDA

JL124BZA

JL124SCA

JL124SDA

Controlling Document

38510/11005, AMEND.2 CIR.F REV B

Processing

MIL-STD-883, Method 5004

Quality Conformance Inspection

MIL-STD-883, Method 5005

Subgrp Description
Temp (°C)

1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125
11	Switching tests at	-55

(Absolute Maximum Ratings)

(Note 1)

Power Dissipation	
CERDIP	400mW
CERPACK	350mW
CERAMIC SOIC	350mW
Supply Voltage	
V+	36Vdc or ± 18 Vdc
Input Voltage Differential	
	30Vdc
Input Voltage	
	-0.03Vdc to +32Vdc
Input Current	
(Note 3)	
(Vin < -0.3 Vdc)	10 to 0.1mA
Output Short-Circuit to GND	
(Note 4)	
(One Amplifier)	
V+ \leq 15Vdc and TA = 25 C	Continuous
Operating Temperature Range	
	-55 C \leq Ta \leq +125 C
Maximum Junction Temperature	
(Note 2)	175 C
Storage Temperature Range	
	-65 C \leq Ta \leq +150 C
Lead Temperature	
(Soldering, 10 seconds)	260 C
Thermal Resistance	
ThetaJA	
CERDIP	(Still Air) 120 C/W
	(500LF/Min Air Flow) 51 C/W
CERPACK	(Still Air) 140 C/W
	(500LF/Min Air Flow) 116 C/W
CERAMIC SOIC	(Still Air) 140 C/W
	(500LF/Min Air Flow) 116 C/W
ThetaJC	
CERDIP	35 C/W
CERPACK	60 C/W
CERAMIC SOIC	60 C/W
Package Weight	
CERDIP	TBD
CERPACK	460mg
CERAMIC SOIC	410mg
ESD Tolerance	
(Note 5)	250 V

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 2: The maximum power dissipation must be derated at elevated temperatures and is dictated by Tjmax (maximum junction temperature), ThetaJA (package junction to ambient thermal resistance), and TA (ambient temperature). The maximum allowable power dissipation at any temperature is P_{dmax} = (Tjmax - TA) / ThetaJA or the number given in the Absolute Maximum Ratings, whichever is lower.

(Continued)

- Note 3: This input current will only exist when the voltage at any of the input leads is driven negative. It is due to the collector-base junction of the input PNP transistors becoming forward biased and thereby acting as input diode clamps. In addition to this diode action, there is also lateral NPN parasitic transistor action on the IC chip. This transistor action can cause the output voltages of the op amps to go to the V₊ voltage level (or to ground for a large overdrive) for the time duration that an input is driven negative. This is not destructive and normal output states will re-establish when the input voltage, which was negative, again returns to a value greater than -0.3 VDC (at 25 C).
- Note 4: Short circuits from the output to V₊ can cause excessive heating and eventual destruction. When considering short circuits to ground, the maximum output current is approximately 40 mA independent of the magnitude of V₊. At values of supply voltage in excess of +15 VDC, continuous short-circuits can exceed the power dissipation ratings and cause eventual destruction. Destructive dissipation can result from simultaneous shorts on all amplifiers.
- Note 5: Human body model, 1.5K ohms in series with 100 pF.

Electrical Characteristics

DC PARAMETERS

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
Vio	Input Offset Voltage	Vcc+ = 30V, Vcc- = Gnd, Vcm = -15V			-5	5	mV	1
					-7	7	mV	2, 3
		Vcc+ = 2V, Vcc- = -28V, Vcm = 13V			-5	5	mV	1
					-7	7	mV	2, 3
		Vcc+ = 5V, Vcc- = Gnd, Vcm = -1.4V			-5	5	mV	1
					-7	7	mV	2, 3
		Vcc+ = 2.5V, Vcc- = -2.5V, Vcm = 1.1V			-5	5	mV	1
					-7	7	mV	2, 3
Iio	Input Offset Current	Vcc+ = 30V, Vcc- = Gnd, Vcm = -15V			-30	30	nA	1, 2
					-75	75	nA	3
		Vcc+ = 2V, Vcc- = -28V, Vcm = 13V			-30	30	nA	1, 2
					-75	75	nA	3
		Vcc+ = 5V, Vcc- = Gnd, Vcm = -1.4V			-30	30	nA	1, 2
					-75	75	nA	3
		Vcc+ = 2.5V, Vcc- = -2.5V, Vcm = 1.1V			-30	30	nA	1, 2
					-75	75	nA	3
+Iib	Input Bias Current	Vcc+ = 30V, Vcc- = Gnd, Vcm = -15V			-150	+0.1	nA	1, 2
					-300	+0.1	nA	3
		Vcc+ = 2V, Vcc- = -28V, Vcm = 13V			-150	+0.1	nA	1, 2
					-300	+0.1	nA	3
		Vcc+ = 5V, Vcc- = Gnd, Vcm = -1.4V			-150	+0.1	nA	1, 2
					-300	+0.1	nA	3
		Vcc+ = 2.5V, Vcc- = -2.5V, Vcm = 1.1V			-150	+0.1	nA	1, 2
					-300	+0.1	nA	3

Electrical Characteristics

DC PARAMETERS (Continued)

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
-I _{ib}	Input Bias Current	V _{cc+} = 30V, V _{cc-} = Gnd, V _{cm} = -15V			-150	+0.1	nA	1, 2
					-300	+0.1	nA	3
		V _{cc+} = 2V, V _{cc-} = -28V, V _{cm} = 13V			-150	+0.1	nA	1, 2
					-300	+0.1	nA	3
		V _{cc+} = 5V, V _{cc-} = Gnd, V _{cm} = -1.4V			-150	+0.1	nA	1, 2
					-300	+0.1	nA	3
		V _{cc+} = 2.5V, V _{cc-} = -2.5V, V _{cm} = 1.1V			-150	+0.1	nA	1, 2
					-300	+0.1	nA	3
+PSRR	Power Supply Rejection Ratio	V _{cc-} = Gnd, V _{cm} = -1.4V, 5V ≤ V _{cc} ≤ 30V			-100	100	uV/V	1, 2, 3
CMRR	Common Mode Rejection Ratio				76		dB	1, 2, 3
I _{os+}	Output Short Circuit Current	V _{cc+} = 30V, V _{cc-} = Gnd, V _o = +25V			-70		mA	1, 2, 3
I _{cc}	Power Supply Current	V _{cc+} = 30V, V _{cc-} = Gnd				3	mA	1, 2
						4	mA	3
Delta V _{io} /Delta T	Input Offset Voltage Temperature Sensitivity	+25 °C ≤ T _A ≤ +125 °C, +V _{cc} = 5V, -V _{cc} = 0V, V _{cm} = -1.4V	3		-30	30	uV/°C	2
		-55 °C ≤ T _A ≤ +25 °C, +V _{cc} = 5V, -V _{cc} = 0V, V _{cm} = -1.4V	3		-30	30	uV/°C	3
Delta I _{io} /Delta T	Input Offset Current Temperature Sensitivity	+25 °C ≤ T _A ≤ +125 °C, +V _{cc} = 5V, -V _{cc} = 0V, V _{cm} = -1.4V	3		-400	400	pA/°C	2
		-55 °C ≤ T _A ≤ +25 °C, +V _{cc} = 5V, -V _{cc} = 0V, V _{cm} = -1.4V	3		-700	700	pA/°C	3
V _{ol}	Logical "0" Output Voltage	V _{cc+} = 30V, V _{cc-} = Gnd, R _L = 10K Ohms				35	mV	4, 5, 6
		V _{cc+} = 30V, V _{cc-} = Gnd, I _{ol} = 5mA				1.5	V	4, 5, 6
		V _{cc+} = 4.5V, V _{cc-} = Gnd, I _{ol} = 2uA				0.4	V	4, 5, 6
V _{oh}	Logical "1" Output Voltage	V _{cc+} = 30V, V _{cc-} = Gnd, I _{oh} = -10mA			27		V	4, 5, 6
		V _{cc+} = 4.5V, V _{cc-} = Gnd, I _{oh} = -10mA			2.4		V	4, 5
					2.3		V	6

Electrical Characteristics

DC PARAMETERS (Continued)

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
Avs+	Voltage Gain	Vcc+ = 30V, Vcc- = Gnd, 1V ≤ Vo ≤ 26V, Rl = 10K Ohms	1		50		V/mV	4
			1		25		V/mV	5, 6
		Vcc+ = 30V, Vcc- = Gnd, 5V ≤ Vo ≤ 20V, Rl = 2K Ohms	1		50		V/mV	4
			1		25		V/mV	5, 6
Avs	Voltage Gain	Vcc+ = 5V, Vcc- = Gnd, 1V ≤ Vo ≤ 2.5V, Rl = 10K Ohms	1		10		V/mV	4, 5, 6
		Vcc+ = 5V, Vcc- = Gnd, 1V ≤ Vo ≤ 2.5V, Rl = 2K Ohms	1		10		V/mV	4, 5, 6
+Vop	Maximum Output Voltage Swing	Vcc+ = 30V, Vcc- = Gnd, Vo = +30V, Rl = 10K Ohms			27		V	4, 5, 6
		Vcc+ = 30V, Vcc- = Gnd, Vo = +30V, Rl = 2K Ohms			26		V	4, 5, 6
Vio(a)	Tempco Screen		4			2.3	mV	
Vio(b)	Tempco Screen		4			2.5	mV	
Iio(a)	Tempco Screen		4			20	nA	
Iio(b)	Tempco Screen		4			16	nA	
+Iib(a)	Tempco Screen		4			16	nA	
+Iib(b)	Tempco Screen		4			10	nA	
+Iib(c)	Tempco Screen		4			13	nA	
-Iib(a)	Tempco Screen		4			16	nA	
-Iib(b)	Tempco Screen		4			10	nA	
-Iib(c)	Tempco Screen		4			13	nA	
PSRR	Tempco Screen		4			17	uV	

Electrical Characteristics

AC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)
AC: +Vcc = 30V, -Vcc = 0V

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
TR(tr)	Transient Response: Rise Time	+Vcc = 30V, -Vcc = Gnd				1	uS	7, 8A, 8B
TR(os)	Transient Response: Overshoot	+Vcc = 30V, -Vcc = Gnd				50	%	7, 8A, 8B
Sr+	Slew Rate: Rise	+Vcc = 30V, -Vcc = Gnd			0.1		V/uS	7, 8A, 8B
Sr-	Slew Rate: Fall	+Vcc = 30V, -Vcc = Gnd			0.1		V/uS	7, 8A, 8B
NI(BB)	Noise Broadband	+Vcc = 15V, -Vcc = -15V, BW = 10Hz to 5KHz	5			15	uV/rms	7
NI(PC)	Noise Popcorn	+Vcc = 15V, -Vcc = -15V, Rs = 20K Ohms	2			50	uV/pk	7
Cs	Channel Separation	+Vcc = 30V, -Vcc = Gnd	5		80		dB	7
		+Vcc = 30V, -Vcc = Gnd, Vin = 1V and 16V, Rl = 2K Ohms	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, A to B	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, A to C	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, A to D	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, B to A	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, B to C	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, B to D	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, C to A	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, C to B	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, C to D	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, D to A	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, D to B	5		80		dB	7
		Rl = 2K Ohms, Vin = 1V and 16V, D to C	5		80		dB	7

Electrical Characteristics

DC PARAMETERS: DRIFT VALUES

(The following conditions apply to all the following parameters, unless otherwise specified.)
 DC: "Delta calculations performed on JAN S and QMLV devices at group B, subgroup 5 only".

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
Vio	Input Offset Voltage	Vcc+ = 30V, Vcc- = Gnd, Vcm = -15V			-1	1	mV	1
+Iib	Input Bias Current	Vcc+ = 30V, Vcc- = Gnd, Vcm = -15V			-15	15	nA	1
-Iib	Input Bias Current	Vcc+ = 30V, Vcc- = Gnd, Vcm = -15V			-15	15	nA	1

Note 1: V/mV = K.

Note 2: Test on either A360, J273 AC or bench test.

Note 3: Calculated parameters.

Note 4: Temp. Co. DLOG readings will print and MNET transfer will occur only in Test Mode 2 = 1. Bin 5 is a potential Temp. Co. failure.

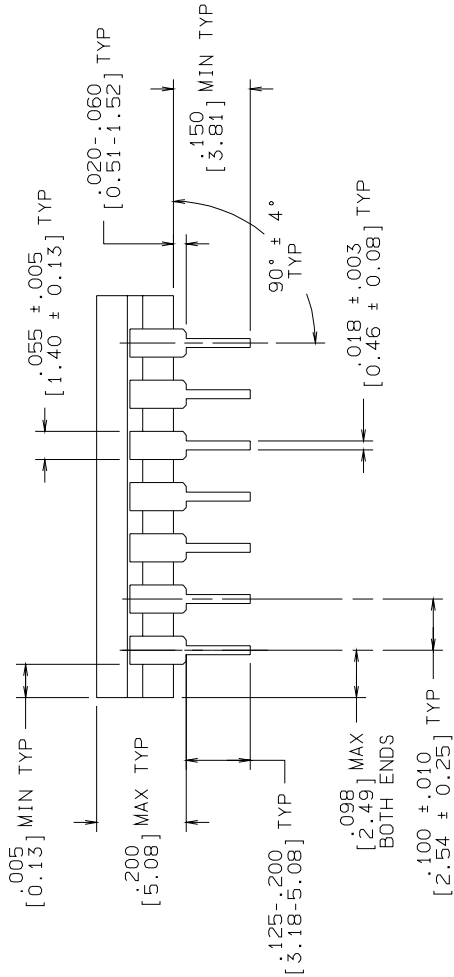
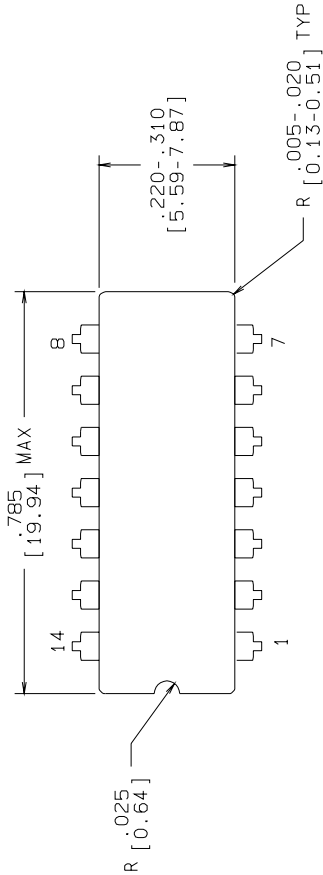
Note 5: Tested on LTX Channel Separation and Noise test tape.

Graphics and Diagrams

GRAPHICS#	DESCRIPTION
05275HRA4	CERPACK (W), 14 LEAD (B/I CKT)
09173HRA2	CERDIP (J), 14 LEAD (B/I CKT)
J14ARH	CERDIP (J), 14 LEAD (P/P DWG)
P000254B	CERAMIC SOIC (WG), 14 LEAD (PINOUT)
P000288A	CERDIP (J), 14 LEAD (PINOUT)
P000474A	CERPACK (W), 14 LEAD (PIN OUT)
W14BRN	CERPACK (W), 14 LEAD (P/P DWG)
WG14ARC	CERAMIC SOIC (WG), 14LD (P/P DWG)

See attached graphics following this page.

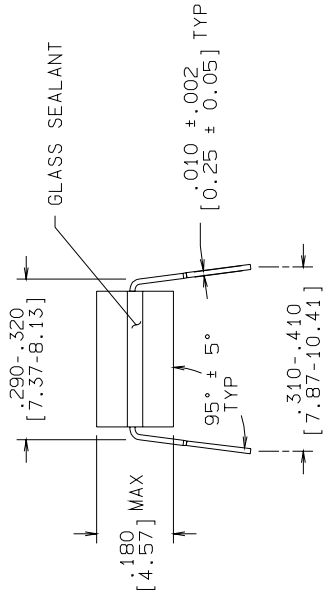
R E V I S I O N S				
LTR	DESCRIPTION	E.C.N.	DATE	BY/APP'D
H	REVISE PER CURRENT STD; REDRAW	10001	09/15/93	TL/



CONTROLLING DIMENSION: INCH

NOTES: UNLESS OTHERWISE SPECIFIED

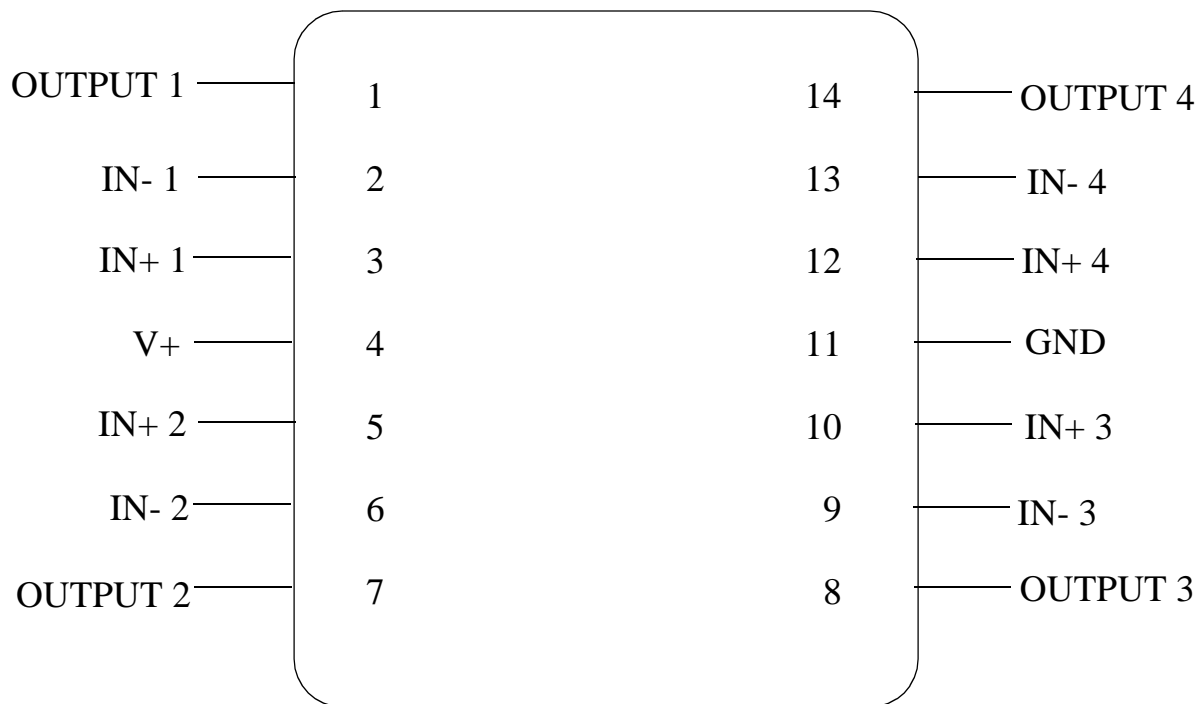
1. LEAD FINISH TO BE 200 MICROMETERS / 5.08 MICROMETERS MINIMUM SOLDER MEASURED AT THE CREST OF THE MAJOR FLATS.
2. JEDEC REGISTRATION MO-036, VARIATION AB, DATED 04/1981.



MIL/AERO MIL-M-38510
CONFIGURATION CONTROL CONFIGURATION CONTROL

APPROVALS	DATE	NATIONAL SEMICONDUCTOR CORPORATION		
DRAWN LEQUANG	09/15/93	2900 Semiconductor Drive, Santa Clara, CA 95052-8090		
DFTG. CHK.				
ENGR. CHK.				
APPROVAL				
PROJECTION		SCALE	SIZE	DRAWING NUMBER
		N/A	B	MKT-J14A
		DO NOT SCALE	DRAWING	SHEET 1 OF 1
				REV H

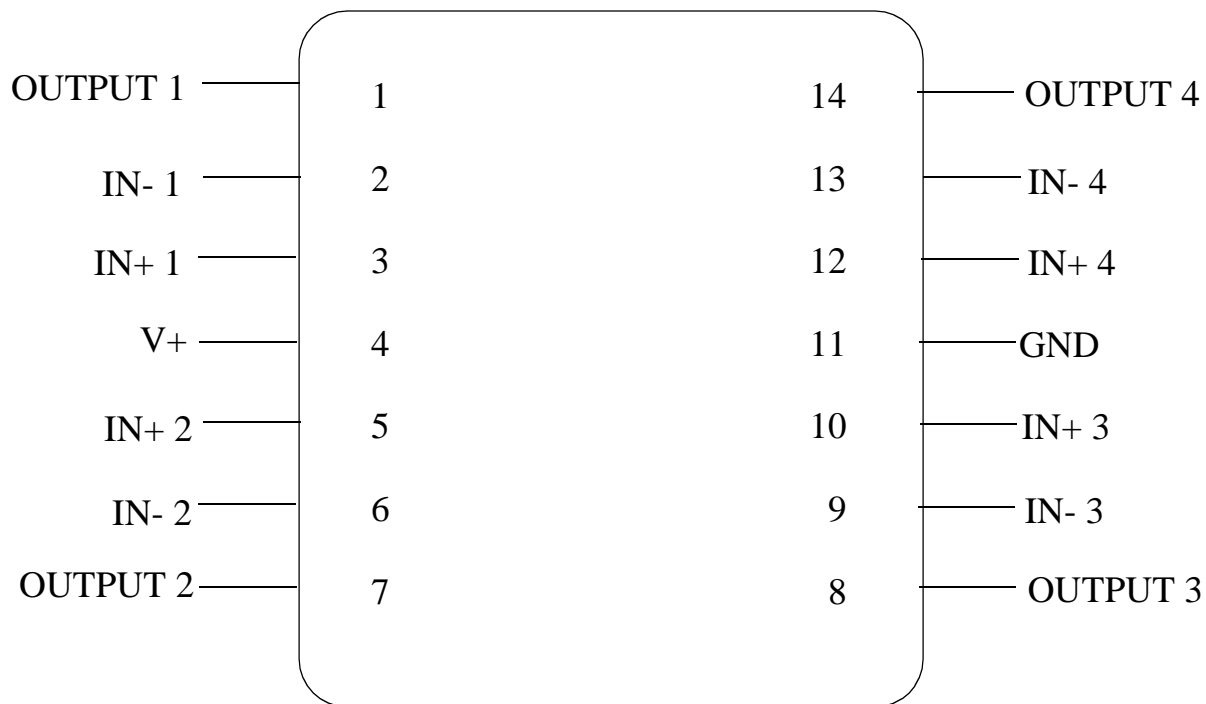
CERDIP (J) ,
14 LEAD,



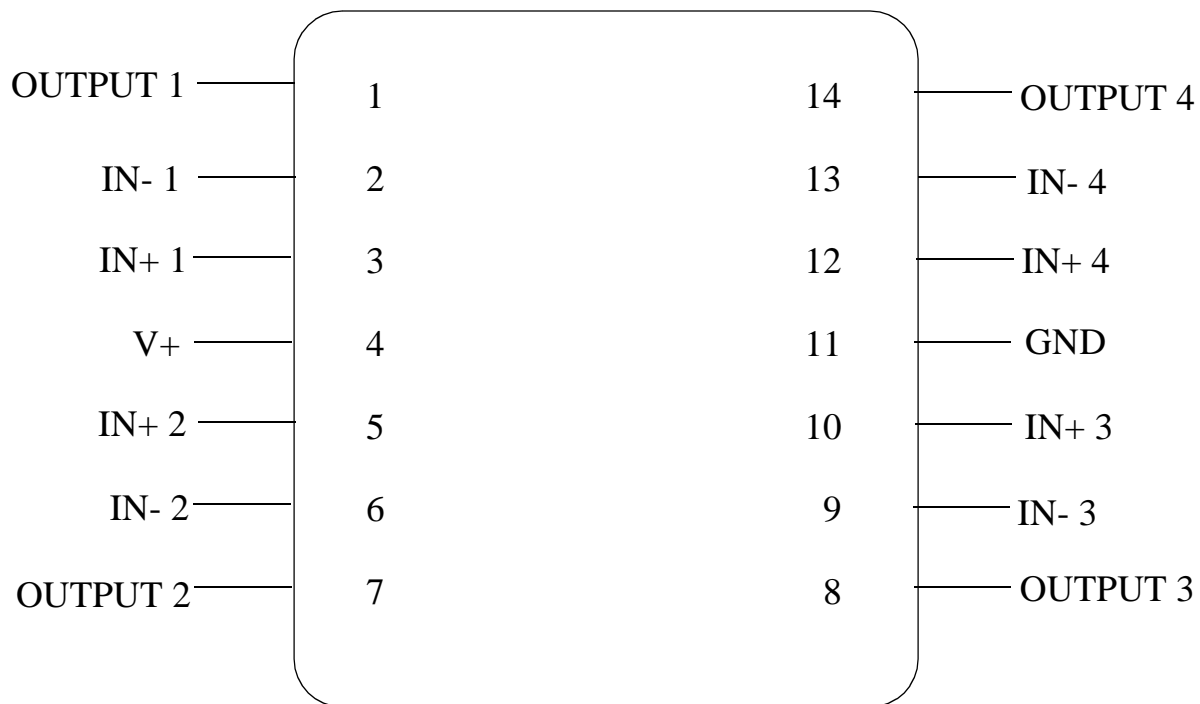
LM124AWG, LM124WG
 14 - LEAD CERAMIC SOIC
 CONNECTION DIAGRAM
 TOP VIEW
 P000254B



National Semiconductor™
 MIL/AEROSPACE OPERATIONS
 2900 SEMICONDUCTOR DRIVE
 SANTA CLARA, CA 95050

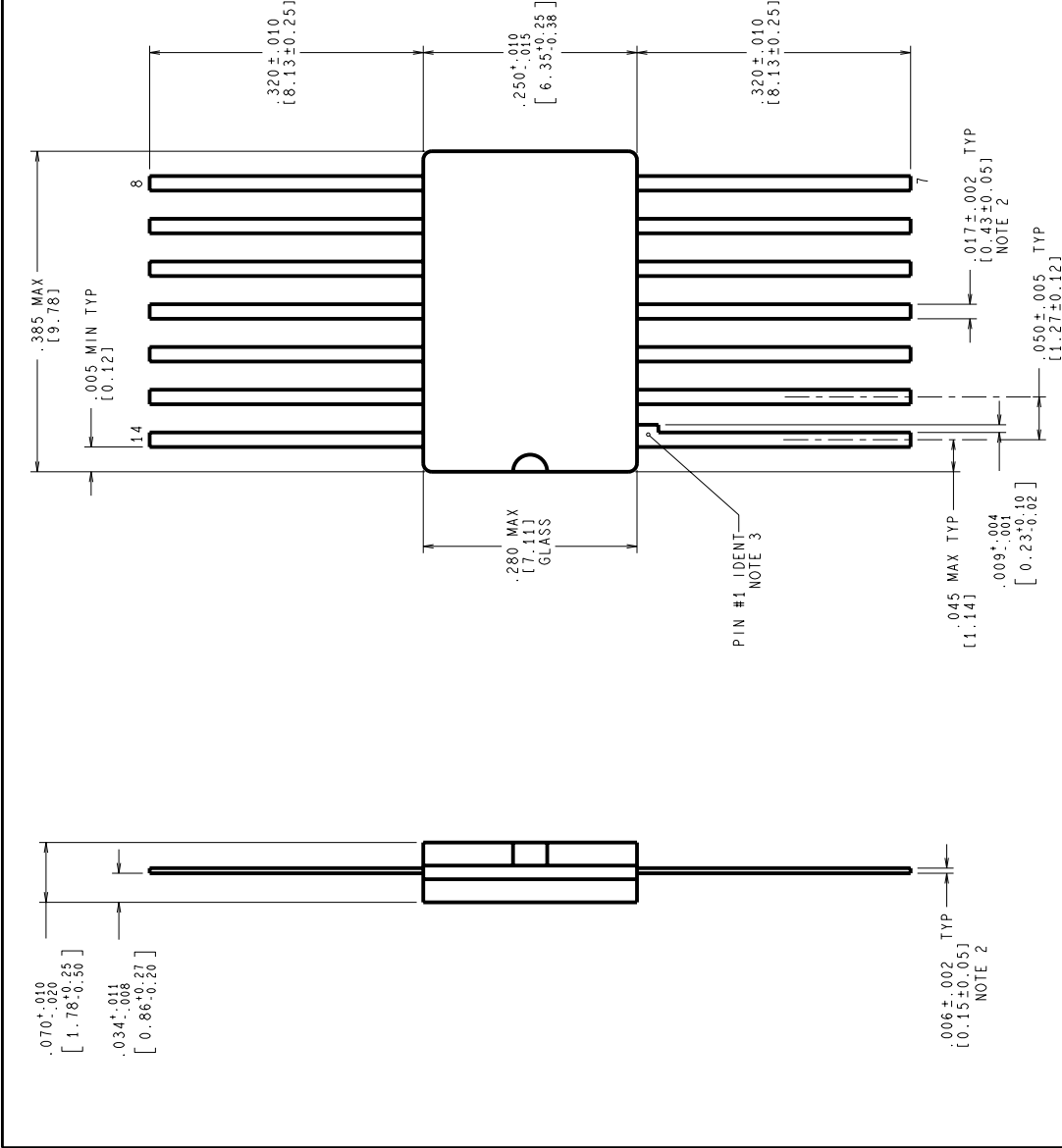


LM124AJ, LM124J
 14 - LEAD DIP
 CONNECTION DIAGRAM
 TOP VIEW
 P000288A



LM124AW, LM124W
14 - LEAD CERAMIC CERPACK
CONNECTION DIAGRAM
TOP VIEW
P000474A

REVISIONS			
LTR	DESCRIPTION	E.C.N.	DATE
L	REVISE AND REDRAW PER NEW STANDARD.	10513	07/26/94
M	.017±.002 WAS .017±.020.	10655	10/21/94
N	L/F THRS. .008±.002 WAS .005±.001; UPDATE NOTES 1 & 2; REMOVE NOTE 4; UPDATE MILAERO STAMP; DUAL DIM'S WERE INCHES ONLY.	11005	06/08/95
			MS/



MIL-I-38535 CONFIGURATION CONTROL

CONTROLLING DIMENSION IS INCH
VALUES IN [] ARE MILLIMETERS

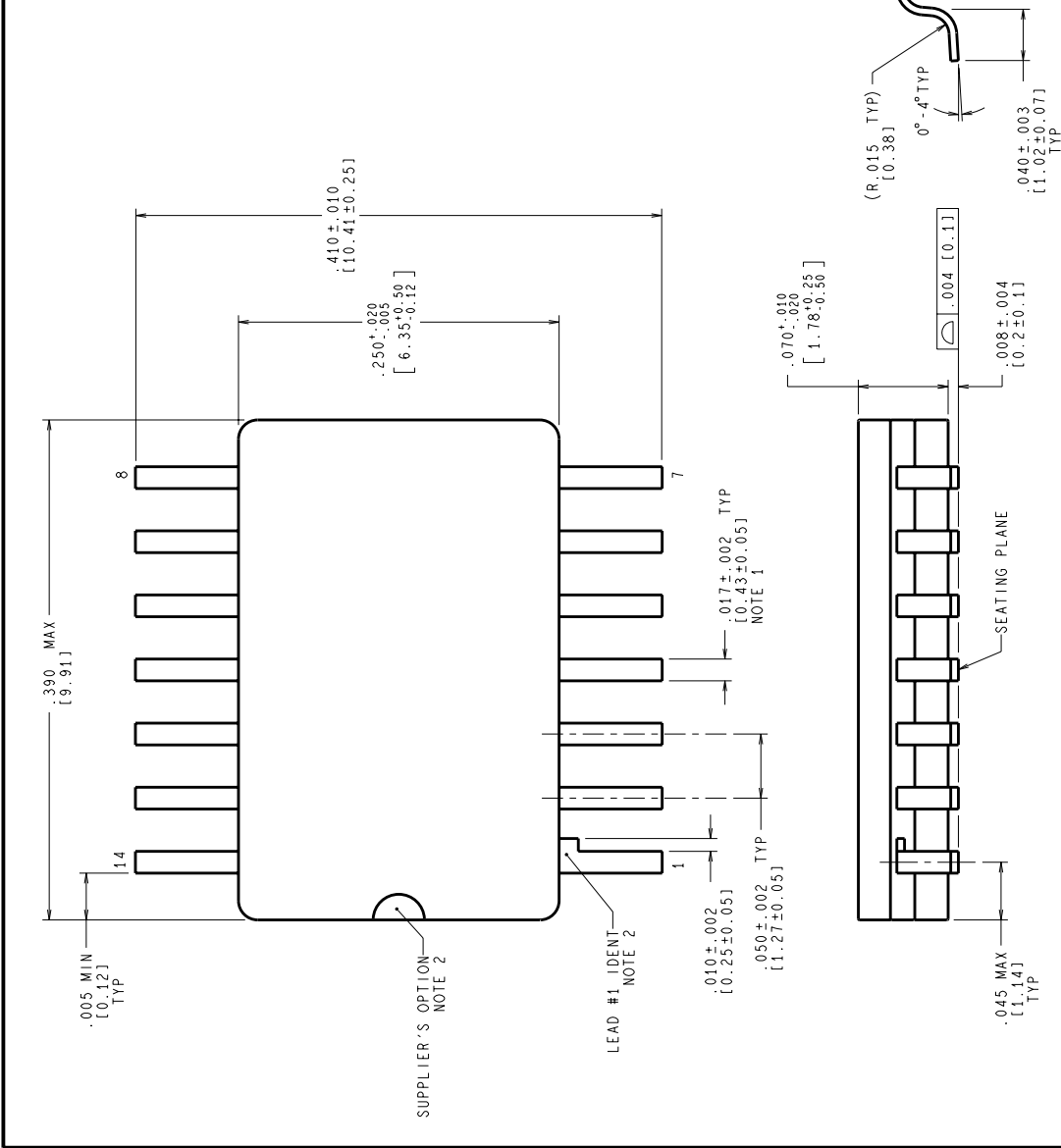
- NOTES: UNLESS OTHERWISE SPECIFIED.
- LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-I-38535 TO A MINIMUM THICKNESS OF 200 MICRONS/ 5.08 MICROMETERS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE.
 - MAXIMUM LIMIT MAY BE INCREASED BY .003 INCHES/ 0.08 MILLIMETERS AFTER LEAD FINISH APPLIED.
 - LEAD 1 IDENTIFICATION SHALL BE:
 - A NOTCH OR OTHER MARK WITHIN THIS AREA
 - A TAB ON LEAD 1, EITHER SIDE

APPROVALS		DATE
DRY	<i>D. F. Grady</i>	07/26/94
SPR	CHK.	
ENGR	CHK.	
PROJECTION		
SCALE	N/A	C
SIZE	C	MKT-W14B
REV		N
DO NOT SCALE DRAWING		
SHEET 1 of 1		

National Semiconductor
2500 Semiconductor Dr., Santa Clara, CA 95052-8000

CERPACK, 14 LEAD

REVISIONS			
LTR	DESCRIPTION	E.C.N.	DATE
A	RELEASE TO DOCUMENT CONTROL	11375	02/29/1996
B	LD PITCH TOL WAS $\pm .005$; CHANGE LD RADIUS TO REF DIM; REMOVE THE OTHER R .006 $\pm .002$; DIM .040 $\pm .003$ WAS .037 $\pm .003$	11442	04/19/1996
C	R .015 [0.38] WAS R .006 [0.15]	11839	10/08/1997



MIL-PRF-38535 CONFIGURATION CONTROL

CONTROLLING DIMENSION IS INCH
VALUES IN | | ARE MILLIMETERS

- NOTES: UNLESS OTHERWISE SPECIFIED
- LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-PRF-38535 TO A MINIMUM THICKNESS OF 200 MICRONS/5.08 MICROMETERS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE. MAXIMUM LIMIT MAY BE INCREASED BY .003 IN/ 0.08mm AFTER LEAD FINISH APPLIED.
 - LEAD 1 IDENTIFICATION SHALL BE:
 - A NOTCH OR OTHER MARK WITHIN THIS AREA
 - A TAB ON LEAD 1, EITHER SIDE
 - NO JEDEC REGISTRATION AS OF FEBRUARY 1996.

APPROVALS		DATE	BY/APP'D	
DESIGN	MARYA SUCHY	02/29/96	DATE	BY/APP'D
TEST	CHK.		MS/KH	
ENG	CHK.		MS/KH	
PROJECTION			SCALE	SIZE
INCH			N/A	C
MIL			DO NOT SCALE	DRAWING
DRAWING NUMBER			SIZE	REV
(SC) MKT-WG14A			C	C
SHEET 1 of 1				

National Semiconductor
2000 Semiconductor Dr., Santa Clara, CA 95052-8000

**CERPACK,
14 LEAD,
GULL WING**

Revision History

Rev	ECN #	Rel Date	Originator	Changes
1A0	M0003654	03/28/02	Rose Malone	Update MDS - MJLM124-X, Rev. 0B1 to Fully Released MDS, MJLM124-X, Rev. 1A0. Parameters Delta Vio/Delta T and Delta Iio/Delta T changed from $+25\text{ C} \leq \text{TA} \leq +125\text{ C}$ and $-55\text{ C} \leq \text{TA} \leq +25\text{ C}$. Is Now, $+25\text{ C} \leq \text{TA} \leq +125\text{ C}$, $+V_{cc} = 5\text{V}$, $-V_{cc} = 0\text{V}$, $V_{cm} = -1.4\text{V}$ and $-55\text{ C} \leq \text{TA} \leq +25\text{ C}$, $+V_{cc} = 5\text{V}$, $-V_{cc} = 0\text{V}$, $V_{cm} = -1.4\text{V}$. To clarify the Tempco test Conditions.
1B1	M0003979	03/28/02	Rose Malone	Update MDS: MJLM124-X, Rev. 1A0 to MJLM124-X, Rev. 1B1. Added WG pkg to Main Table, Absolute Maximum Ratings Section and Graphics Section.